

DTP15N80SJ-VB Datasheet

N-Channel 800V (D-S) Super Junction Power MOSFET

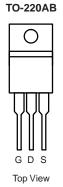
PRODUCT SUMMARY					
V_{DS} (V) at T_J max.	800				
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V 0.38				
Q _g max. (nC)	96				
Q _{gs} (nC)	11				
Q _{gd} (nC)	21				
Configuration	Single				

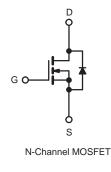
FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- · Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting





ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	800	v	
Gate-Source Voltage			V _{GS}	± 30	V	
Continuous Drain Current (T,ı = 150 °C)	V _{GS} at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$	I.	15		
Continuous Drain Current (1) = 150°C)	$T_{\rm C} = 100 ^{\circ}{\rm C}$	I _D	12	A		
Pulsed Drain Current ^a			I _{DM}	46		
Linear Derating Factor				1.7	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	297	mJ	
Maximum Power Dissipation			PD	208	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope T _J = 125 °C		dV/dt	37	V/ns		
Reverse Diode dV/dt ^d			26	v/ns		
Soldering Recommendations (Peak Temperature) ^c for 10 s			300	°C		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		62		*CAN		
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.7		°C/W				
SPECIFICATIONS ($T_J = 25 \text{ °C}$, u	Inless otherwi	se noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static							-	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D =	250 µA	800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I _D = 1 mA	-	0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
		,	$V_{GS} = \pm 20$	V	-	-	± 100	nA
Gate-Source Leakage	I _{GSS}	,	$V_{GS} = \pm 30$	V	-	-	± 1	μA
		V _{DS} = 800 V, V _{GS} = 0 V		-	-	1	-	
Zero Gate Voltage Drain Current	I _{DSS}			V, T _J = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		I _D = 8 A	-	0.38	-	Ω
Forward Transconductance	g fs	V _{DS}	= 30 V, I _D	= 8 A	-	6.3	-	S
Dynamic					1		1	1
Input Capacitance	C _{iss}		$V_{ee} = 0$	/	-	1720	-	
Output Capacitance	C _{oss}	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	80	-		
Reverse Transfer Capacitance	C _{rss}			-	4	-		
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	$V_{DS} = 0 V \text{ to } 520 V, V_{GS} = 0 V - \frac{63}{213}$		-	pF			
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	213	-		
Total Gate Charge	Qg	V _{GS} = 10 V I _D = 8 A, V _{DS} = 520 V		-	48	96	nC	
Gate-Source Charge	Q _{gs}			-	11	-		
Gate-Drain Charge	Q _{gd}				-	21	-	
Turn-On Delay Time	t _{d(on)}				-	18	36	
Rise Time	t _r	$\begin{array}{c c c c c c c c c c c c c c c c c c c $		$V_{DD} = 520 \text{ V}, \text{ I}_{D} = 8 \text{ A},$ - 24		48 ns		
Turn-Off Delay Time	t _{d(off)}	V _{GS} =	= 10 V, R _g	= 9.1 Ω			96	
Fall Time	t _f				-		50	
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.8	-	Ω	
Drain-Source Body Diode Characteristic	cs	1			1	1	1	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	15	A	
Pulsed Diode Forward Current	I _{SM}			-	46			
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 8 A, V _{GS} = 0 V		-	-	1.2	V	
Reverse Recovery Time	t _{rr}	T _J = 25 °C, $I_F = I_S = 8 \text{ A}$, dl/dt = 100 A/µs, $V_B = 400 \text{ V}$		-	325	-	ns	
Reverse Recovery Charge	Q _{rr}			-	4.6	-	μC	
Reverse Recovery Current	I _{RRM}	dl/dt = 1	ου Α/μs, \	/ _R = 400 V	_	20	_	A
	'KKIM				1			<i>,</i> ,

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

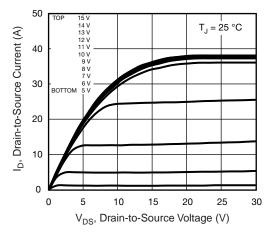


Fig. 1 - Typical Output Characteristics

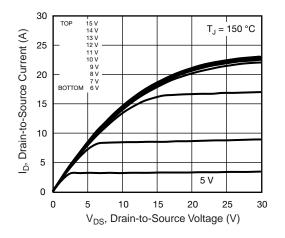


Fig. 2 - Typical Output Characteristics

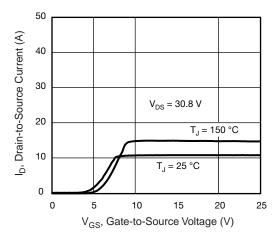


Fig. 3 - Typical Transfer Characteristics

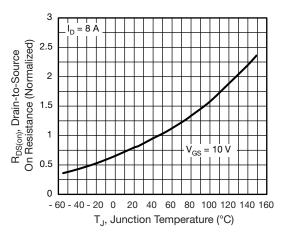


Fig. 4 - Normalized On-Resistance vs. Temperature

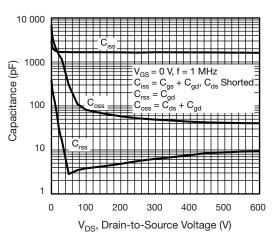


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

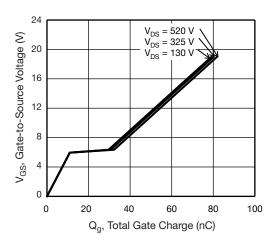


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

DTP15N80SJ-VB



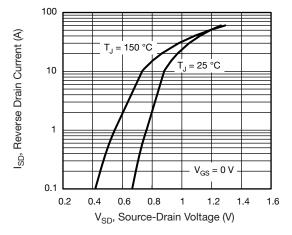
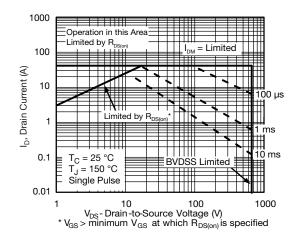


Fig. 7 - Typical Source-Drain Diode Forward Voltage





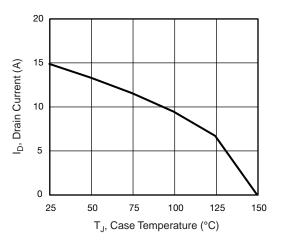


Fig. 9 - Maximum Drain Current vs. Case Temperature

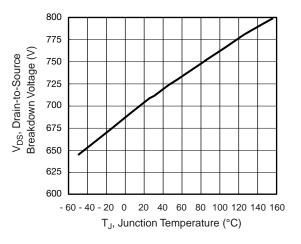


Fig. 10 - Temperature vs. Drain-to-Source Voltage

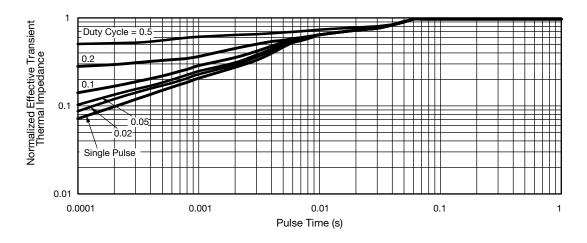


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



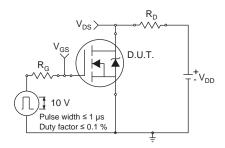


Fig. 12 - Switching Time Test Circuit

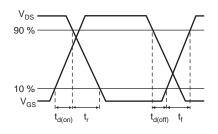


Fig. 13 - Switching Time Waveforms

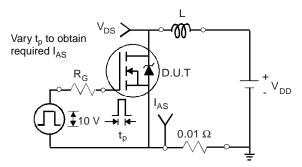


Fig. 14 - Unclamped Inductive Test Circuit

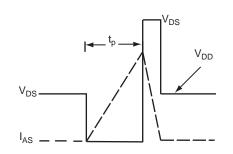


Fig. 15 - Unclamped Inductive Waveforms

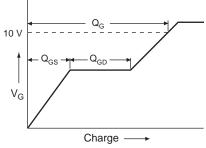


Fig. 16 - Basic Gate Charge Waveform

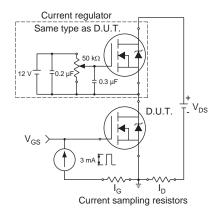
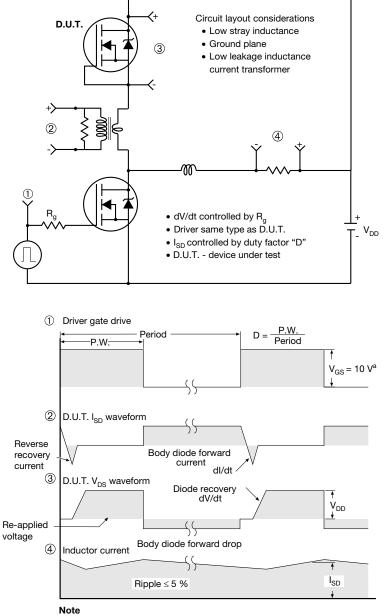


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

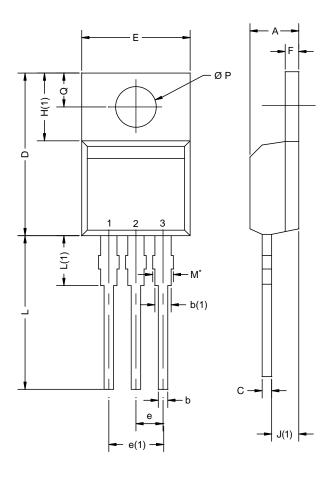


a. $V_{GS} = 5$ V for logic level devices

Fig. 18 - For N-Channel



TO-220AB



	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12- DWG: 547	-0208-Rev. N, 1	08-Oct-12		

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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